

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|---------|--|--|------------------|---------|------------------|
| L1 | 6124974 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/01/29 16:00 |
| L3 | 4735498 | (transient non-transient soft hard brief enduring fleeting non-fleeting evanescent non-evanescent) | US-PGPUB; USPAT; USOCR | OR | ON | 2008/01/29 16:01 |
| L4 | 6 | categor\$5 near3 3 same (photomask mask reticle) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/01/29 16:02 |
| S1 | 13 | peterson near2 ingrid.in. hoff near2 (mike michael).in. wiley near2 jim. in. | US-PGPUB; USPAT | OR | OFF | 2007/01/31 14:39 |
| S2 | 4 | "6268093".pn. "6373975".pn. "6701004".pn. "5965306".pn. | US-PGPUB; USPAT | OR | OFF | 2006/12/27 18:45 |
| S3 | 1 | "20040091142" | US-PGPUB | OR | OFF | 2007/01/31 17:04 |
| S5 | 2480728 | focus exposure illumination aperture coherence | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/17 10:09 |
| S6 | 5708802 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/17 10:12 |
| S7 | 997466 | photomask lithograph\$3 semiconductor near mask pcb circuit near2 board reticle wafer | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/06 13:19 |

EAST Search History

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| S8 | 11954984 | different distinct many several plural\$4 var\$3 chang\$3 distinctive various numerous separate | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/01/17 10:17 |
| S9 | 273699 | S8 near3 S5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/01/17 10:19 |
| S10 | 148789 | S6 with S7 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/01/17 10:18 |
| S11 | 7 | (subtract\$3 tak\$3 adj away remov\$3) near3 (non-transient) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/17 17:40 |
| S12 | 1 | S9 and S10 and S11 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/17 10:20 |
| S13 | 10220 | S9 and S10 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/17 10:22 |
| S14 | 451 | (subtract\$3 tak\$3 adj away remov\$3) near3 (hard near3 S6) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/17 17:43 |

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| S15 | 5 | S13 and S14 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/17 10:25 |
| S16 | 5708802 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/09/25 13:39 |
| S17 | 17875 | (non-transient hard enduring non-fleeting non-evanescent) near3 S16 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/18 14:30 |
| S18 | 453 | (subtract\$3 tak\$3 adj away remov\$3) near3 S17 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/09/20 11:59 |
| S19 | 997466 | photomask lithograph\$3 semiconductor near mask pcb circuit near2 board reticle wafer | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/01/17 17:44 |
| S20 | 38 | S19 near3 S16 and S18 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/17 17:44 |
| S21 | 37975 | (transient non-transient soft hard brief enduring fleeting non-fleeting evanescent non-evanescent) near3 S16 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/01/24 16:25 |

EAST Search History

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| S22 | 4 | ("5308722" "6421457").PN. OR ("6701004").URPN. | US-PGPUB; USPAT; USOCR | OR | OFF | 2007/01/18 14:24 |
| S23 | 5711627 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/18 14:30 |
| S24 | 22954 | (transient soft brief fleeting evanescent) near3 S23 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/18 15:06 |
| S25 | 17897 | (non-transient hard enduring non-fleeting non-evanescent) near3 S23 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 15:24 |
| S26 | 21 | (subtract\$3 tak\$3 adj away remov\$3) near3 S25 same S24 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/18 14:46 |
| S27 | 1580 | S24 same S25 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/18 15:06 |
| S28 | 6952 | 382/141-145,147,149,182,185.ccls. 348/87,131.ccls. 359/436,385.ccls. 356/401.ccls. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/01/18 15:08 |

EAST Search History

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| S29 | 5711627 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/18 15:08 |
| S30 | 22954 | (transient soft brief fleeting evanescent) near3 S29 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/18 15:08 |
| S31 | 17897 | (non-transient hard enduring non-fleeting non-evanescent) near3 S29 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/18 15:08 |
| S32 | 1580 | S30 same S31 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/18 15:08 |
| S33 | 6 | S32 and S28 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/01/18 15:10 |
| S34 | 1 | (transient non-transient soft hard brief enduring fleeting non-fleeting evanescent non-evanescent) and "6701004".pn. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/01/29 11:13 |
| S35 | 5725702 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/31 12:15 |

EAST Search History

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| S36 | 212 | (transient non-transient soft hard brief enduring fleeting non-fleeting evanescent non-evanescent) near3 S35 and "382".clas. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/06 13:18 |
| S37 | 1 | ("2004/0091142").URPN. | USPAT | OR | OFF | 2007/01/31 13:33 |
| S38 | 4 | ("5308722" "6421457").PN. OR ("6701004").URPN. | US-PGPUB; USPAT; USOCR | OR | OFF | 2007/01/31 13:35 |
| S39 | 6974 | 382/141-145,147,149,182,185.ccls. 348/87,131.ccls. 359/436,385.ccls. 356/401.ccls. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/01/31 14:40 |
| S40 | 712 | reference near3 compar\$3 and S39 | US-PGPUB; USPAT | OR | ON | 2007/09/20 15:53 |
| S41 | 5725702 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/31 15:19 |
| S43 | 1001769 | photomask lithograph\$3 semiconductor near mask pcb circuit near2 board reticle wafer | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/01/31 15:23 |
| S44 | 144 | reference near3 compar\$3 with S41 and S39 and S43 near3 S41 | US-PGPUB; USPAT | OR | ON | 2007/01/31 15:52 |
| S47 | 1981 | (bin binning) with region | US-PGPUB; USPAT | OR | ON | 2007/01/31 15:54 |
| S48 | 12 | S39 and S47 | US-PGPUB; USPAT | OR | ON | 2007/01/31 15:56 |
| S49 | 182 | (high bright) with (low dark) with (filter\$3 remov\$3) with (pre-process\$3 preprocess\$3) | US-PGPUB; USPAT | OR | ON | 2007/01/31 15:58 |
| S50 | 1 | S39 and S49 | US-PGPUB; USPAT | OR | ON | 2007/01/31 15:58 |
| S51 | 29 | "382".clas. and S49 | US-PGPUB; USPAT | OR | ON | 2007/01/31 16:03 |

EAST Search History

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|-----|-------|--|--|----|-----|------------------|
| S52 | 12091 | (multiple many several array) near3 (CCD sensor detector) with pixel | US-PGPUB; USPAT | OR | ON | 2007/01/31 16:04 |
| S53 | 157 | S39 and S52 | US-PGPUB; USPAT | OR | ON | 2007/01/31 16:13 |
| S54 | 1225 | flag\$3 with review\$3 | US-PGPUB; USPAT | OR | ON | 2007/01/31 16:38 |
| S55 | 15 | S39 and S54 | US-PGPUB; USPAT | OR | ON | 2007/01/31 16:44 |
| S56 | 267 | (remov\$3 filter\$3) with (high same low) near3 intensity | US-PGPUB; USPAT | OR | ON | 2007/01/31 16:48 |
| S57 | 28 | "382".clas. and S56 | US-PGPUB; USPAT | OR | ON | 2007/01/31 16:45 |
| S58 | 49 | (threshold\$3) with (high same low) near3 intensity and "382".clas. | US-PGPUB; USPAT | OR | ON | 2007/01/31 16:49 |
| S59 | 9 | (threshold\$3) with (high same low) near3 intensity and S39 | US-PGPUB; USPAT | OR | ON | 2007/01/31 16:50 |
| S61 | 40 | S58 not S59 | US-PGPUB; USPAT | OR | ON | 2007/01/31 16:51 |
| S66 | 60928 | "382".clas. S39 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/01/31 17:12 |
| S67 | 246 | (remov\$3 filter\$3 threshold\$3) near3 (dark same bright) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/31 17:13 |
| S68 | 12 | (remov\$3 filter\$3 threshold\$3) near3 (high same low) near3 (brightness lightness) and S66 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/31 17:13 |
| S69 | 55 | S67 and S66 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/31 17:18 |

EAST Search History

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|-----|---------|---|--|----|-----|------------------|
| S70 | 9 | S69 and S39 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/31 17:18 |
| S71 | 122 | lithograph\$3 near7 aerial adj image | US-PGPUB; USPAT | OR | ON | 2007/05/22 16:34 |
| S72 | 2 | aerial adj image same non-aerial adj image | US-PGPUB; USPAT | OR | ON | 2007/05/22 16:35 |
| S73 | 1 | "20040091142" | US-PGPUB; USPAT | OR | ON | 2007/05/22 16:37 |
| S74 | 6009 | (photomask photoreticle reticle mask) near3 (defect\$1 inspect\$3) | US-PGPUB; USPAT | OR | ON | 2007/05/22 16:39 |
| S76 | 5862607 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/05 16:15 |
| S77 | 203 | reticle near3 S76 and lithograph\$3 and aerial adj imag\$3 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/05 16:16 |
| S78 | 7191 | 382/141-145,147,149,182,185.ccls. 348/87,131.ccls. 359/436,385.ccls. 356/401.ccls. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/06 15:24 |
| S79 | 27 | S78 and S77 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 11:01 |
| S80 | 1197 | aerial adj image adj measur\$6 adj system AIMS with (reticle mask) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 12:20 |

EAST Search History

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| S81 | 5862607 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 11:12 |
| S82 | 37029 | S81 near3 (mask reticle) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 11:42 |
| S83 | 54 | S80 same S82 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 11:45 |
| S84 | 1 | 08/950620.app. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 11:45 |
| S85 | 1037 | aerial adj imag\$3 with (reticle mask) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 11:50 |
| S86 | 140 | S85 same S82 not S83 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 11:50 |
| S87 | 1 | "5795688".pn. | USPAT | OR | OFF | 2007/06/06 12:05 |
| S88 | 1201 | aerial adj imag\$3 adj measur\$6 adj system AIMS with (reticle mask) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 12:20 |

EAST Search History

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| S89 | 5862607 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 13:18 |
| S90 | 39263 | (transient non-transient soft hard brief enduring fleeting non-fleeting evanescent non-evanescent) near3 S89 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/09/20 15:51 |
| S91 | 611729 | photomask semiconductor near mask reticle mask | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/09/25 13:38 |
| S93 | 18494 | (non-transient hard enduring non-fleeting non-evanescent) near3 S89 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/06 13:26 |
| S94 | 526 | S93 near7 S91 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/06 13:27 |
| S95 | 237 | S93 near7 S91 with (non-aerial print\$3 project\$3 etch\$3) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/06 13:30 |
| S96 | 0 | S93 near7 S91 with (non-aerial) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/06 13:28 |

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| S97 | 7191 | 382/141-145,147,149,182,185.ccls. 348/87,131.ccls. 359/436,385.ccls. 356/401.ccls. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/06 13:28 |
| S98 | 1 | S95 and S97 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/06 13:29 |
| S99 | 30 | S93 and S97 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/06 13:30 |
| S10 0 | 7191 | 382/141-145,147,149,182,185.ccls. 348/87,131.ccls. 359/436,385.ccls. 356/401.ccls. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/06/06 15:24 |
| S10 1 | 5862607 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 15:24 |
| S10 2 | 18495 | (non-transient hard enduring non-fleeting non-evanescent) near3 S101 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 15:28 |
| S10 3 | 30 | S102 and S100 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 15:25 |

EAST Search History

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| S10 4 | 92 | S100 and (pinhole pindot extrusion) same (mask reticle photomask) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/06/06 15:28 |
| S10 6 | 1056 | mask adj layout | USPAT | OR | OFF | 2007/09/20 11:58 |
| S10 8 | 5981851 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/09/20 11:59 |
| S10 9 | 19021 | (non-transient hard enduring non-fleeting non-evanescent) near3 S108 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/09/20 11:59 |
| S11 0 | 496 | (subtract\$3 tak\$3 adj away remov\$3) near3 S109 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/09/20 11:59 |
| S11 1 | 7372 | 382/141-145,147,149,182,185.ccls. 348/87,131.ccls. 359/436,385.ccls. 356/401.ccls. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/09/20 15:18 |
| S11 2 | 3 | S110 and S111 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/09/20 12:00 |
| S11 3 | 3616 | aerial adj imag\$3 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/09/20 15:18 |

EAST Search History

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| S11 4 | 132689 | (transient with non-transient soft with hard brief with enduring fleeting with non-fleeting evanescent with non-evanescent) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/09/20 15:59 |
| S11 5 | 5304 | (determin\$3 locat\$4 find\$4 flag\$4 extract\$3) with S114 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/09/20 16:00 |
| S11 6 | 7372 | 382/141-145,147,149,182,185.ccls. 348/87,131.ccls. 359/436,385.ccls. 356/401.ccls. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/09/20 15:53 |
| S11 7 | 4 | S116 and S115 | US-PGPUB; USPAT | OR | ON | 2007/09/20 15:53 |
| S11 8 | 136 | (determin\$3 locat\$4 find\$4 flag\$4 extract\$3) with S114 same (reticle wafer mask photomask semiconductor) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/09/20 15:58 |
| S11 9 | 5981851 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/09/20 16:00 |
| S12 0 | 1365 | (transient near3 S119 with non-transient near3 S119 soft near3 S119 with hard near3 S119 brief near3 S119 with enduring near3 S119 fleeting near3 S119 with non-fleeting near3 S119 evanescent near3 S119 with non-evanescent near3 S119) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/09/20 16:00 |

EAST Search History

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| S12 1 | 14 | (determin\$3 locat\$4 find\$4 flag\$4 extract\$3) with S120 same (reticle wafer mask photomask semiconductor) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/09/20 16:04 |
| S12 2 | 158 | (anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5) near5 (bin\$3 stor\$4 flag\$4) near3 (region area pixels pels) near3 (around surround\$4 proximat\$3 border\$3) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/09/25 13:41 |
| S12 3 | 48 | "382".clas. and S122 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/09/25 13:42 |
| S12 4 | 3 | "6902855".pn. "6757645".pn. "6171737".pn. | USPAT | OR | OFF | 2008/01/19 19:39 |
| S12 5 | 3 | "6902855".pn. "6757645".pn. "6171737".pn. | US-PGPUB; USPAT | OR | ON | 2008/01/24 11:43 |
| S12 6 | 76 | ("20020019729" "20020035461" "4812962" "5051598" "5182718" "5241185" "5242770" "5256505" "5282140" "5316878" "5326659" "5340700" "5424154" "5432714" "5447810" "5532090" "5533148" "5538815" "5553273" "5572598" "5631110" "5657235" "5663893" "5702848" "5705301" "5707765" "5740068" "5795688" "5801954" "5804340" "5815685" "5825647" "5827623" "5847959" "5849440" "5862058" "5863682" "6009250" "6009251" "6011911" "6014456" "6016357" "6076465" "6078738" "6081658" "6081659" "6130750").PN. OR ("6757645").URPN. | US-PGPUB; USPAT; USOCR | OR | OFF | 2008/01/24 16:25 |
| S12 7 | 6118438 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/01/24 16:26 |

EAST Search History

| | | | | | | |
|----------|---------|---|--|----|-----|------------------|
| S12 8 | 7 | (transient non-transient soft hard brief enduring fleeting non-fleeting evanescent non-evanescent) near3 S127 and S126 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/01/29 14:38 |
| S13 0 | 76 | ("20020019729" "20020035461" "4812962" "5051598" "5182718" "5241185" "5242770" "5256505" "5282140" "5316878" "5326659" "5340700" "5424154" "5432714" "5447810" "5532090" "5533148" "5538815" "5553273" "5572598" "5631110" "5657235" "5663893" "5702848" "5705301" "5707765" "5740068" "5795688" "5801954" "5804340" "5815685" "5825647" "5827623" "5847959" "5849440" "5862058" "5863682" "6009250" "6009251" "6011911" "6014456" "6016357" "6076465" "6078738" "6081658" "6081659" "6130750").PN. OR ("6757645").URPN. | US-PGPUB; USPAT; USOCR | OR | OFF | 2008/01/29 11:11 |
| S13 1 | 6124974 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/01/29 11:12 |
| S13 2 | 5244159 | (transient non-transient soft hard brief enduring fleeting non-fleeting evanescent non-evanescent) | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/01/29 11:13 |
| S13 3 | 231198 | (class\$7 sort\$3 identif\$7 recogni\$7 determin\$7 find\$3 search\$3) near3 S131 | US-PGPUB; USPAT; USOCR | OR | OFF | 2008/01/29 11:15 |
| S13 6 | 1 | "6757645".pn. and print\$8 with potential | US-PGPUB; USPAT | OR | ON | 2008/01/29 11:21 |

EAST Search History

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|----------|---------|--|--|----|-----|------------------|
| S13 7 | 10 | S130 and S132 with S131 and S133 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2008/01/29 15:58 |
| S13 9 | 6124974 | anomaly defect imperfection blemish crack deformity error fault flaw hole irregular\$7 scratch contamina\$5 | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2008/01/29 14:42 |
| S14 0 | 2 | (transient non-transient soft hard brief enduring fleeting non-fleeting evanescent non-evanescent) near3 S139 with subtract\$4 same (reticle mask photomask lithograph\$3) | US-PGPUB; USPAT; USOCR | OR | ON | 2008/01/29 14:43 |